

Notice of References Cited

Application/Control No.

09/910,371

Applicant(s)/Patent Under

Reexamination

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Examiner

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Art Unit

2857

Page 1 of 1

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M	US-			

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NON-PATENT DOCUMENTS

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	V	Sematech, "The Engineers Statistics Internet (ESI) Handbook: Grubbs' Test for Outliers." 1999.			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.